



RADIO TEST REPORT

Test Report No. : 32GE0048-HO-01-A-R1

Applicant : FUJITSU TEN LIMITED
Type of Equipment : Radio Detection and Ranging Device for Vehicle
Model No. : FT0041A
FCC ID : BABFT0041A
Test regulation : FCC Part 15 Subpart C: 2012
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This report is a revised version of 32GE0048-HO-01-A. 32GE0048-HO-01-A is replaced with this report.

Date of test: March 2 to 6, 2012

Representative test engineer:

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Approved by:

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NVLAP LAB CODE: 200572-0

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13-EM-F0429

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SECTION 1: Customer information

Company Name : FUJITSU TEN LIMITED
Address : 2-28, Gosho-dori 1-Chome, Hyogo-ku, Kobe 652-8510, Japan
Telephone Number : +81-78-682-2159
Facsimile Number : +81-78-671-7160
Contact Person : Shotatsu Yo

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Radio Detection and Ranging Device for Vehicle
Model No. : FT0041A
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : February 22, 2012
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: FT0041A (referred to as the EUT in this report) is the Radio Detection and Ranging Device for Vehicle.

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2012, final revised on February 1, 2012
Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.253 Operation within the bands 46.7-46.9GHz and 76.0-77.0GHz.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC power line Conducted Emission measurements ----- IC: RSS-Gen 7.2.4	FCC: Section 15.207 ----- IC: RSS-Gen 7.2.4	N/A	N/A	*1)
26dB Bandwidth	FCC: "MILLIMETER WAVE TEST PROCEDURES" ----- IC: -	FCC: Section 15.253(e) ----- IC: RSS-210 A13.1.5	See data.	Complied	Radiated
Power Density	FCC: "MILLIMETER WAVE TEST PROCEDURES" ----- IC: -	FCC: Section 15.253(b), (d) ----- IC: RSS-210 A13.1.2(1)		Complied	Radiated
Spurious Emissions	FCC: ANSI C63.4:2003, "MILLIMETER WAVE TEST PROCEDURES" ----- IC: RSS-Gen 4.9	FCC: Section 15.253(c), (d) ----- IC: RSS-210 A13.1.2(2), A13.1.4, RSS-Gen 7.2.3	5.2dB 38127.930MHz, AV Vertical	Complied	Radiated
Frequency Stability	FCC: "MILLIMETER WAVE TEST PROCEDURES" ----- IC: RSS-Gen 4.7, 7.2.4	FCC: Section 15.253(e) ----- IC: RSS-210 A13.1.5	See data.	Complied	Radiated

*1) The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line
Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

Millimeter wave measurement was performed accordance with FCC KDB 200443 (MILLIMETER WAVE TEST PROCEDURES).

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Radiated
Receiver Spurious Emission	IC: RSS-Gen 4.10	IC: RSS-Gen 6	- *1)	Complied	Radiated

*1) Transmitting and receiving is operating simultaneously. The limits are same as transmitter spurious emission limits. Therefore, these results were included within transmitter results.

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Radiated emission					
	(3m*)(+dB)				(1m*)(+dB)	
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz 40GHz
No.1	4.2dB	5.0dB	5.1dB	4.7dB	5.7dB	4.4dB
No.2	4.1dB	5.2dB	5.1dB	4.8dB	5.6dB	4.3dB
No.3	4.5dB	5.0dB	5.2dB	4.8dB	5.6dB	4.5dB
No.4	4.7dB	5.2dB	5.2dB	4.8dB	5.6dB	5.1dB

*3m/1m/0.5m = Measurement distance

Radiated emission (+dB)	
40GHz-50GHz	3.9dB
50GHz-75GHz	5.1dB
75GHz-110GHz	5.4dB
110GHz-170GHz	5.2dB
170GHz-260GHz	5.2dB

Spurious Emissions test (1m)

The data listed in this test report has enough margin, more than the site margin.

Power Density

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Data of EMI, Test instruments, and Test set up

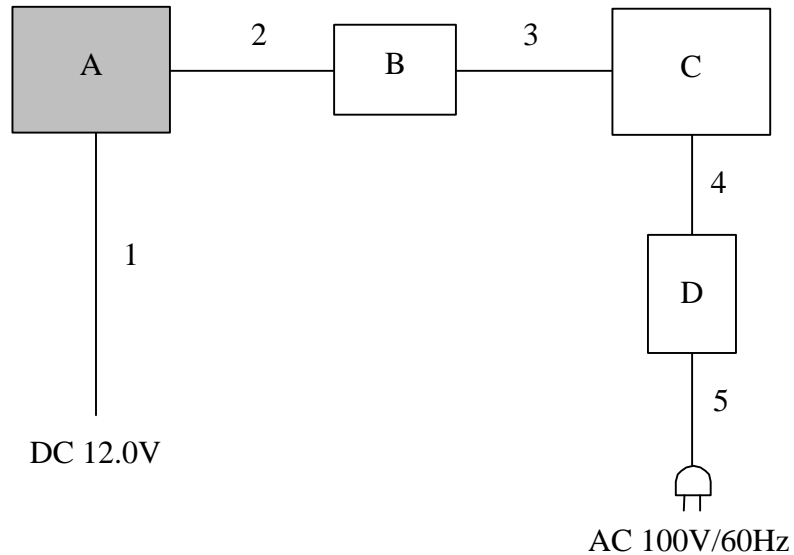
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Mode	Test Item
Operating mode (In motion) *1)	26dB Bandwidth Power Density Spurious Emission Frequency Stability
Operating mode (Not in motion)	Power Density
End users cannot change the settings of the output power of the product.	
*1) All test items were performed on "In motion" mode, since output power is higher than "Not in motion" mode.	

4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Radio Detection and Ranging Device for Vehicle	FT0041A	301121K2AFF	FUJITSU TEN LIMITED	EUT
B	CANcaseXL	007129	021086	vector	-
C	Laptop PC	FMVNB3Y8	R6900746	FUJITSU LIMITED	-
D	AC Adaptor	FMV-AC317	06222578A	FUJITSU LIMITED	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	1.5	Unshielded	Unshielded	-
2	CAN Cable	1.5	Unshielded	Unshielded	-
3	USB Cable	1.9	Shielded	Shielded	-
4	DC Cable	1.8	Unshielded	Unshielded	-
5	AC Cable	2.0	Unshielded	Unshielded	-

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SECTION 5: Radiated Emission (Spurious Emission, Power Density)

Test Procedure

[Up to 40GHz]

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m(9kHz – 10GHz), 0.5m by 0.5m(10GHz – 40GHz) , raised 0.8m(9kHz – 10GHz), 1.5m(10GHz – 40GHz) above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane. The height of the measuring antenna varied between 1 and 4m (frequency 9kHz – 30MHz: loop antenna was fixed height at 1.0m) and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength. The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer. The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table. When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

Frequency	9kHz-150kHz	150kHz-30MHz	30MHz-1GHz	1GHz-231GHz	
Instrument used	Test Receiver	Test Receiver	Test Receiver	Spectrum Analyzer	
Detector	QP, AV	QP, AV	QP	PK	AV
IF Bandwidth	BW 200Hz	BW 9kHz	BW 120kHz	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz *1)
Test Distance	3m	3m	3m	3m (below 10GHz), 1m *2) (10GHz – 40GHz) Above 40GHz: For more details, refer to next page.	

*1) The test was performed with VBW 10Hz since the emission had continuously except for the Carrier frequency.

*2) Distance Factor: $20 \times \log(3.0\text{m}/1.0\text{m}) = 9.5\text{dB}$

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[Above 40GHz]

The test was performed based on "MILLIMETER WAVE TEST PROCEDURES".
The EUT was placed on a urethane platform, raised 1.5m above the conducting ground plane.
The measurements were performed on handheld method.

Set spectrum analyzer RBW, VBW, span, etc., to the proper values. Note these values. Enable two traces—one set to “clear write,” and the other set to “max hold.”
Begin hand-held measurements with the test antenna (horn) at a distance of 1 m from the EUT in a horizontally polarized position. Slowly adjust its position, entirely covering the plane 1 m from the EUT.
Observation of the two active traces on the spectrum analyzer will allow refined horn positioning at the point(s) of maximum field intensity. Repeat with the horn in a vertically polarized position. If the emission cannot be detected at 1 m, reduce the RBW to increase system sensitivity. Note the value. If the emission still cannot be detected, move the horn closer to the EUT, noting the distance at which a measurement is made.

Note the maximum level indicated on the spectrum analyzer. Adjust this level, if necessary, by the antenna gain, conversion loss of the external mixer and gain of LNA used, at the frequency under investigation. Calculate the field strength of the emission at the measurement distance from the Friis' transmission equation.

[About carrier measurement]

The carrier levels were confirmed at maximum direction of transmission. The maximum direction was searched under carefully since beam-widths are extremely narrow.

The carrier levels were measured in the far field. The distance of the far field was calculated from follow equation.

$$r = \frac{2D^2}{\lambda}$$

where

r is the distance from the radiating element of the EUT to the edge of the far field, in m
D is the largest dimension of both the radiating element and the test antenna (horn), in m
Lambda is the wavelength of the emission under investigation [300/f (MHz)], in m

Antenna	Frequency [GHz]	Lambda [mm]	Maximum Dimention			Far Field Boundary r [m]
			H [mm]	V [mm]	Diagonal D [m]	
Tx1	77.0	3.9	60.41	3.17	0.060	1.9
Tx2	77.0	3.9	50.89	13.4	0.053	1.5

The test was made on EUT at the normal use position since the installation position was decided based on “Theory of operation”.

For the carrier measurement, the measuring antenna was angularly-tilted, since the EUT has angularly-tilted linear polarized antenna.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 9k-231GHz
Test data : APPENDIX
Test result : Pass

SECTION 6: Frequency Stability

Test Procedure

The external mixer was placed in side of the temperature chamber drain hole.

The power supply set to 100 % nominal setting, raise EUT operating temperature to 50 deg. C.

Record the frequency excursion of the EUT emission mask.

Repeat measurements at each 10 deg. C increment down to -20 deg. C.

Varied EUT power supply between 85 % and 115 % of nominal and record the frequency excursion of the EUT emission mask when temperature is 20 deg. C.

Emission mask was measured 26dB bandwidth.

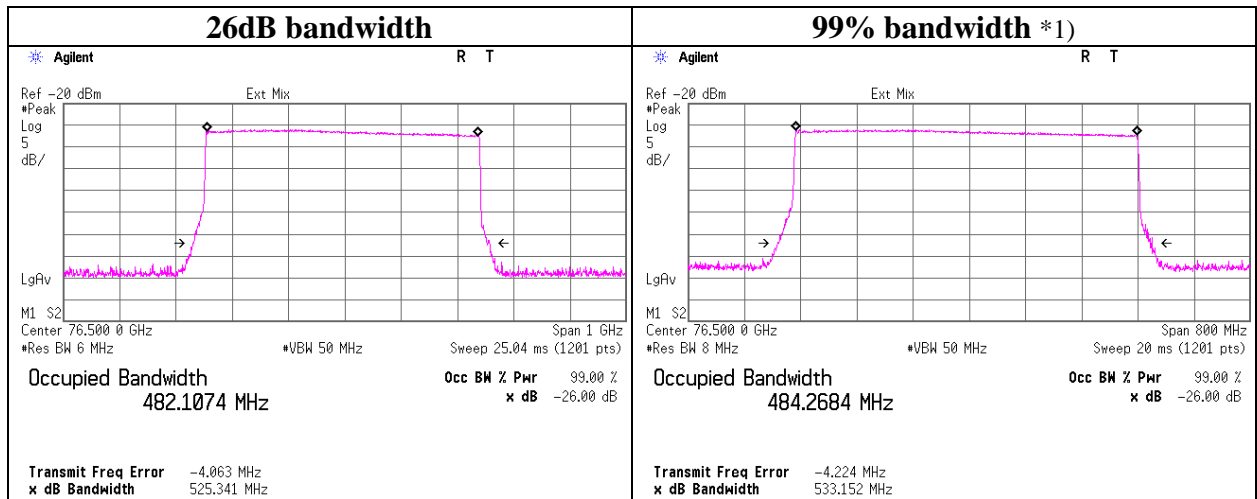
Test data : APPENDIX
Test result : Pass

APPENDIX 1: Data of EMI test

26dB and 99% Bandwidth

Test place	Head Office EMC Lab. No.6 Shielded Room
Report No.	32GE0048-HO-01
Date	03/06/2012
Temperature/ Humidity	25 deg. C / 35% RH
Engineer	Hironobu Ohnishi
Mode	Operating mode (In motion)

Frequency [GHz]	26dB Bandwidth [MHz]	99% Occupied Bandwidth [MHz]
76.500	525.341	484.268



*1) The measurement was performed with Peak detector, Max Hold since the duty cycle was not 100%.

Power Density

Test place : Head Office EMC Lab. No.3 Semi Anechoic Chamber
Report No. : 32GE0048-HO-01
Date : 03/02/2012
Temperature/ Humidity : 22 deg. C / 35% RH
Engineer : Hironobu Ohnishi
Mode : Operating mode (In motion / Not in motion)

Mode	Frequency [GHz]	Measurement Distance [m]	Measured Power [dBm]	Rx Antenna Gain [dBi]	System Loss [dB]	LNA Gain [dB]	Free field Attenuation [dB]
In motion (Tx1)	76.4953	3.0	-67.73	22.33	42.02	0.00	79.66
Not in motion (Tx1)	76.4953	3.0	-74.12	22.33	42.02	0.00	79.66

Mode	Peak EIRP		Specification Distance [m]	Power Density Pk [uW/cm2]	Limit Pk [uW/cm2]	Margin Pk [dB]
	[dBm]	[mW]				
In motion (Tx1)	31.62	1451.7	3.0	1.284	6000	36.70
Not in motion (Tx1)	25.23	333.3	3.0	0.295	20	18.32

Mode	Duty Factor * [dB]	Average EIRP (Peak with Duty Factor)		Specification Distance [m]	Power Density Av [uW/cm2]	Limit Av [uW/cm2]	Margin Av [dB]
		[dBm]	[mW]				
In motion (Tx1)	-6.44	25.18	329.5	3.0	0.291	60	23.14
Not in motion (Tx1)	-6.44	18.79	75.7	3.0	0.067	0.2	4.76

* $10\log(0.227)$: Since duty is 22.7%, Refer to exhibit "Theory of operation"

Calculating formula:

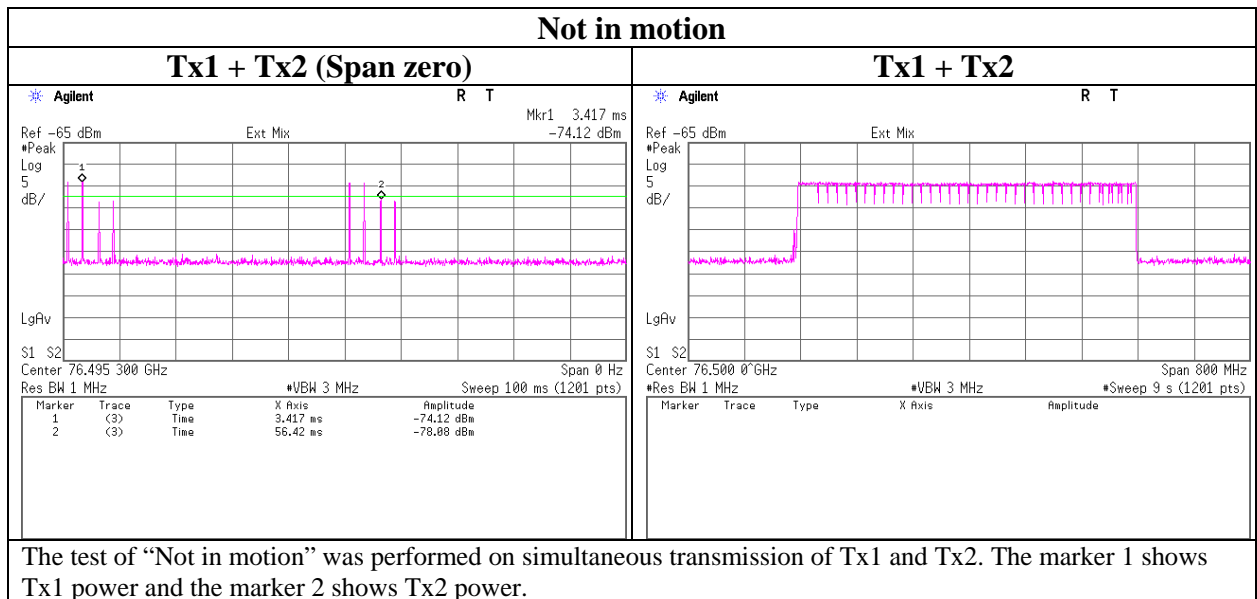
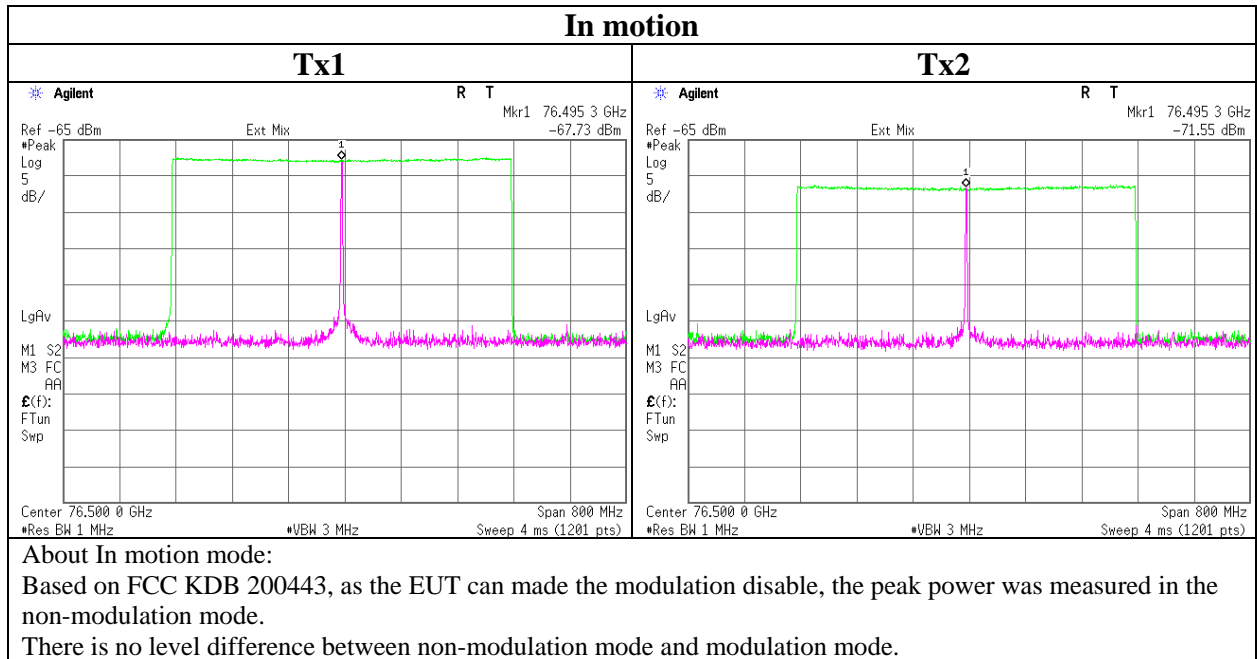
$$\text{Free Field Attenuation} = 10 * \log((4 * \pi * \text{Measurement Distance} / \lambda)^2)$$

$$\text{Peak EIRP} = \text{Measured Power} - \text{Rx Antenna Gain} + \text{System Loss} - \text{LNA Gain} + \text{Free Field Attenuation}$$

$$\text{Average EIRP} = \text{Peak EIRP} * \text{Duty Factor}$$

$$\text{Power Density} = \text{EIRP} / (4 * \pi * \text{Specification Distance}^2)$$

The test was performed on Tx1 mode, since output power is higher than Tx2 mode.



Spurious Emission

Test place : Head Office EMC Lab. No.3 Semi Anechoic Chamber
Report No. : 32GE0048-HO-01
Date : 03/05/2012
Temperature/ Humidity : 23 deg. C / 40% RH
Engineer : Hironobu Ohnishi
(9kHz - 40GHz)
Mode : Operating mode (In motion)

Polarity	Frequency [MHz]	Detector	Reading [dBuV]	Ant.Fac. [dB/m]	Loss [dB]	Gain [dB]	Result [dBuV/m]	Limit [dBuV/m]	Margin [dB]	Remark
Hori	45.000	QP	23.0	12.9	7.4	32.2	11.1	40.0	28.9	No signal.
Hori	49.000	QP	22.6	11.4	7.5	32.2	9.3	40.0	30.7	No signal.
Hori	78.150	QP	27.0	6.4	7.9	32.1	9.2	40.0	30.8	
Hori	86.010	QP	24.3	7.6	8.0	32.1	7.8	40.0	32.2	
Hori	120.000	QP	22.9	13.0	8.4	32.1	12.2	43.5	31.3	
Hori	38127.930	PK	46.7	41.9	-2.9	24.0	61.7	73.9	12.2	
Hori	38127.930	AV	33.6	41.9	-2.9	24.0	48.6	53.9	5.3	VBW=10Hz
Vert	45.000	QP	23.2	12.9	7.4	32.2	11.3	40.0	28.7	No signal.
Vert	49.000	QP	22.7	11.4	7.5	32.2	9.4	40.0	30.6	No signal.
Vert	78.150	QP	31.4	6.4	7.9	32.1	13.6	40.0	26.4	
Vert	86.010	QP	28.8	7.6	8.0	32.1	12.3	40.0	27.7	
Vert	120.000	QP	24.5	13.0	8.4	32.1	13.8	43.5	29.7	
Vert	38127.930	PK	47.4	41.9	-2.9	24.0	62.4	73.9	11.5	
Vert	38127.930	AV	33.7	41.9	-2.9	24.0	48.7	53.9	5.2	VBW=10Hz

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter-Distance factor(above 10GHz)) - Gain(Amplifier)

*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

Distance factor: 10GHz-40GHz $20\log(3.0m/1.0m) = 9.5dB$

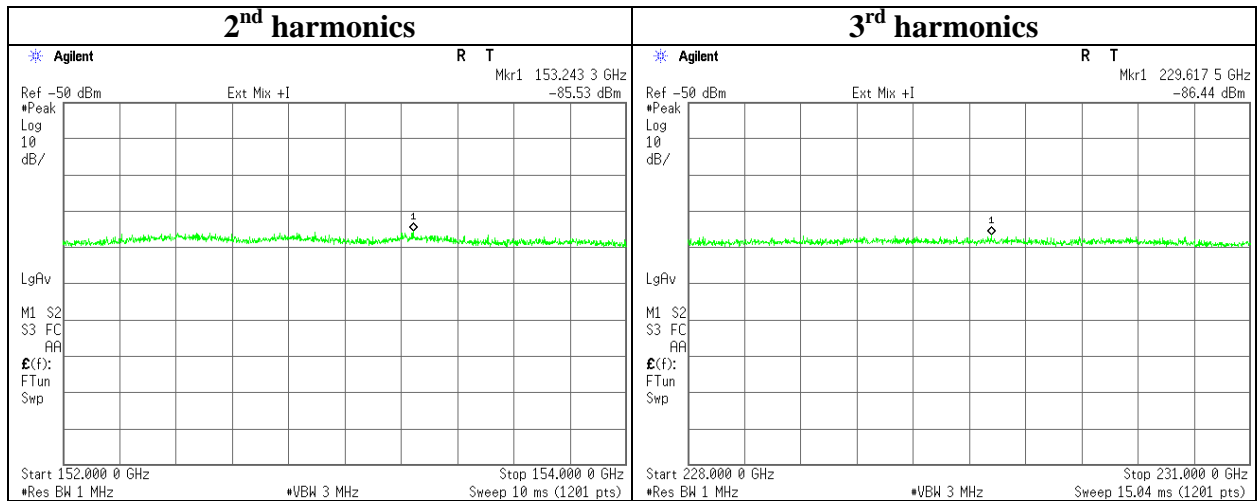
* The average measurement of 38GHz was performed with VBW 10Hz since the emission is continuously radiated.

Spurious Emission (above 40GHz)

Test place	Head Office EMC Lab. No.3 Semi Anechoic Chamber
Report No.	32GE0048-HO-01
Date	03/02/2012
Temperature/ Humidity	22 deg. C / 35% RH
Engineer	Hironobu Ohnishi
	(40-231GHz)
Mode	Operating mode (In motion)

* The peak density is less than the average limit.
 There is no spurious emission from 40GHz to 231GHz except for operating band.

The following shows the measurement results of the harmonics.



Receiver Spurious Emission

Transmitting and receiving is operating simultaneously. The limits are same as transmitter spurious emission limits. Therefore, these results were included within transmitter results.

Frequency Stability

Test place Head Office EMC Lab. No.6 Shielded room
Report No. 32GE0048-HO-01
Date 03/06/2012
Temperature/ Humidity 25 deg. C / 35% RH
Engineer Hironobu Ohnishi
Mode Operating mode (In motion)

Test Condition		Center	Frequency	26dB	Lower	Upper
Temperature	Power Supply	Frequency	Error	Bandwidth	Frequency	Frequency
[deg. C]	[V]	[GHz]	[MHz]	[MHz]	[GHz]	[GHz]
50	12.0	76.500	-4.988	528.576	76.231	76.759
40	12.0	76.500	-4.280	529.416	76.231	76.760
30	12.0	76.500	-3.569	525.277	76.234	76.759
20	12.0	76.500	-3.387	529.502	76.232	76.761
10	12.0	76.500	-2.659	520.150	76.237	76.757
0	12.0	76.500	-2.545	568.329	76.213	76.782
-10	12.0	76.500	-1.539	521.235	76.238	76.759
-20	12.0	76.500	-0.911	519.921	76.239	76.759
20	10.2	76.500	-3.503	523.124	76.235	76.758
20	13.8	76.500	-3.482	525.136	76.234	76.759
20	9.0	76.500	-3.530	523.150	76.235	76.758
20	16.0	76.500	-3.039	522.911	76.236	76.758

Calculating formula:

$$\text{Lower Frequency} = \text{Center Frequency} + \text{Frequency Error} - 26\text{dB Bandwidth} / 2$$

$$\text{Upper Frequency} = \text{Center Frequency} + \text{Frequency Error} + 26\text{dB Bandwidth} / 2$$

APPENDIX 2: Test instruments

EMI test equipment (1/2)

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-03	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE	2012/02/24 * 12
MOS-13	Thermo-Hygrometer	Custom	CTH-180	-	RE	2012/02/06 * 12
MJM-06	Measure	PROMART	SEN1955	-	RE	-
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	RE	2011/04/08 * 12
MHA-07	Horn Antenna	Custom	HO22R	10766-01	RE	2011/10/31 * 12
MCC-140	Microwave Cable	Junkosha	J12J101596-00	JAN-31-12-001	RE	2012/02/24 * 12
MPA-03	Microwave System Power Amplifier	Agilent	83050A	3950M00205	RE	2011/06/15 * 12
MHA-09	Horn Antenna	WiseWave	ARH1523-02	10766-01	RE	2011/10/31 * 12
MPA-08	Pre Amplifier	WiseWave	ALN-61226028-51	11576-01-071	RE	2011/08/27 * 12
MMX-01	Preselected Millimeter Mixer	Agilent	11974V-E01	3001A00412	RE	2011/06/13 * 12
MHA-11	Horn Antenna	WiseWave	ARH1023-02	10766-01	RE	2011/10/31 * 12
MPA-18	Pre Amplifier	AmTechs Corporation	LNA-7511025	9601	RE	2011/08/27 * 12
MMX-02	Harmonic Mixer	Agilent	11970W	2521 A01909	RE	2011/06/14 * 12
MCC-66	Microwave Cable 1G-40GHz	Suhner	SUCOFLEX102	28636/2	RE	2011/04/22 * 12
MCC-67	Microwave Cable 1G-40GHz	Suhner	SUCOFLEX102	28635/2	RE	2011/04/22 * 12
MHA-24	Horn Antenna	Custom Microwave Inc.	HO6R	-	RE	2011/09/19 * 12
MMX-03	Harmonic Mixer	OML Inc.	M06HWD	D100709-1	RE	2011/09/30 * 12
MHA-27	Horn Antenna	Custom Microwave Inc.	HO4R	-	RE	2011/09/19 * 12
MMX-04	Harmonic Mixer	OML Inc.	M04HWD	Y100709-1	RE	2011/09/30 * 12
MCC-135	Microwave Cable	HUBER+SUHNER	SUCOFLEX102	37511/2	RE	2011/08/31 * 12
MDPLX-01	Diplexer	OML Inc.	DPL26	-	RE	2011/09/19 * 12
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE	-
MTR-08	Test Receiver	Rohde & Schwarz	ESCI	100767	RE	2011/08/11 * 12
MLPA-01	Loop Antenna	Rohde & Schwarz	HFH2-Z2	100017	RE	2011/10/19 * 12
MCC-112	Coaxial cable	Fujikura/Suhner/TSJ	5D-2W(10m)/ SFM141(3m)/ sucoform141-PE(1m)/ 421-010(1.5m)/ RFM-E321(Switcher)	-/00640	RE	2011/07/15 * 12
MCC-31	Coaxial cable	UL Japan	-	-	RE	2011/07/28 * 12
MPA-13	Pre Amplifier	SONOMA INSTRUMENT	310	260834	RE	2011/03/04 * 12
MAT-09	Attenuator(6dB)	Weinschel Corp	2	BK7973	RE	2011/11/02 * 12
MBA-03	Biconical Antenna	Schwarzbeck	BBA9106	1915	RE	2011/10/15 * 12
MLA-03	Logperiodic Antenna	Schwarzbeck	USLP9143	174	RE	2011/10/15 * 12
MCC-51	Coaxial cable	UL Japan	-	-	RE	2011/07/15 * 12
MHA-20	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	258	RE	2011/05/23 * 12
MCC-133	Microwave Cable	HUBER+SUHNER	SUCOFLEX104	336164/4(1m) / 340640(5m)	RE	2011/09/07 * 12

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EMI test equipment (2/2)

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MPA-11	MicroWave System Amplifier	Agilent	83017A	MY39500779	RE	2011/03/10 * 12
MHA-16	Horn Antenna 15-40GHz	Schwarzbeck	BBHA9170	BBHA9170306	RE	2011/05/23 * 12
MCH-04	Temperature and Humidity Chamber	Tabai Espec	PL-2KP	14015723	RE	2011/08/22 * 12
MMM-10	DIGITAL HiTESTER	Hioki	3805	051201148	RE	2012/01/13 * 12

The expiration date of the calibration is the end of the expired month.

[Below 40GHz]

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

[Above 40GHz]

Acceptance criteria for untraceable equipment was formulated according to ISO/IEC 17025 5.6.2.2.2, and the regular inspection was performed based on it annually.

For 40-110GHz, power sensor is calibrated by manufacturer, and the measured calibration data is used as in-house reference. The calibration data by manufacturer is checked for acceptance by a calorie meter except for some frequency bands.

For above 110GHz, output level of millimeter wave source module is used as the reference, and inspection by the calorie meter is performed.

Electric power is checked with the calorie meter by measuring resistance and voltage of reference resistor.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

RE: Radiated Emission

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